DISCRETE SEMICONDUCTORS

DATA SHEET

BF245A; BF245B; BF245C N-channel silicon field-effect transistors

Product specification Supersedes data of April 1995 1996 Jul 30



N-channel silicon field-effect transistors

BF245A; BF245B; BF245C

FEATURES

- Interchangeability of drain and source connections
- Frequencies up to 700 MHz.

APPLICATIONS

• LF, HF and DC amplifiers.

DESCRIPTION

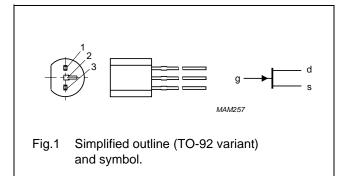
General purpose N-channel symmetrical junction field-effect transistors in a plastic TO-92 variant package.

CA	ш	TI	n	N
	v		v	IA

The device is supplied in an antistatic package. The gate-source input must be protected against static discharge during transport or handling.

PINNING

PIN	SYMBOL	DESCRIPTION
1	d	drain
2	s	source
3	g	gate



QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V _{DS}	drain-source voltage		_	_	±30	V
V_{GSoff}	gate-source cut-off voltage	I _D = 10 nA; V _{DS} = 15 V	-0.25	_	-8	V
V_{GSO}	gate-source voltage	open drain	_	_	-30	V
I _{DSS}	drain current	$V_{DS} = 15 \text{ V}; V_{GS} = 0$				
	BF245A		2	_	6.5	mA
	BF245B		6	_	15	mA
	BF245C		12	_	25	mA
P _{tot}	total power dissipation	T _{amb} = 75 °C	_	_	300	mW
y _{fs}	forward transfer admittance	V _{DS} = 15 V; V _{GS} = 0; f = 1 kHz; T _{amb} = 25 °C	3	_	6.5	mS
C _{rs}	reverse transfer capacitance	V _{DS} = 20 V; V _{GS} = -1 V; f = 1 MHz; T _{amb} = 25 °C	_	1.1	_	pF

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LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{DS}	drain-source voltage		_	±30	V
V_{GDO}	gate-drain voltage	open source	_	-30	V
V_{GSO}	gate-source voltage	open drain	_	-30	V
I_{D}	drain current		_	25	mA
I _G	gate current		_	10	mA
P _{tot}	total power dissipation	up to T _{amb} = 75 °C;	_	300	mW
		up to T _{amb} = 90 °C; note 1	_	300	mW
T _{stg}	storage temperature		-65	+150	°C
Tj	operating junction temperature		_	150	°C

Note

1. Device mounted on a printed-circuit board, minimum lead length 3 mm, mounting pad for drain lead minimum $10 \text{ mm} \times 10 \text{ mm}$.

THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
R _{th j-a}	thermal resistance from junction to ambient	in free air	250	K/W
	thermal resistance from junction to ambient		200	K/W

STATIC CHARACTERISTICS

 $T_i = 25$ °C; unless otherwise specified.

SYMBOL	PARAMETER	PARAMETER CONDITIONS		MAX.	UNIT
V _{(BR)GSS}	gate-source breakdown voltage	$I_G = -1 \mu A; V_{DS} = 0$	-30	_	V
V_{GSoff}	gate-source cut-off voltage	I _D = 10 nA; V _{DS} = 15 V	-0.25	-8.0	V
V_{GS}	gate-source voltage	I _D = 200 μA; V _{DS} = 15 V			
	BF245A		-0.4	-2.2	V
	BF245B		-1.6	-3.8	V
	BF245C		-3.2	-7.5	V
I _{DSS}	drain current	V _{DS} = 15 V; V _{GS} = 0; note 1			
	BF245A		2	6.5	mA
	BF245B		6	15	mA
	BF245C		12	25	mA
I _{GSS}	gate cut-off current	$V_{GS} = -20 \text{ V}; V_{DS} = 0$	_	-5	nA
		$V_{GS} = -20 \text{ V}; V_{DS} = 0; T_j = 125 ^{\circ}\text{C}$	_	-0.5	μΑ

Note

1. Measured under pulse conditions: t_p = 300 $\mu s; \, \delta \leq 0.02.$

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DYNAMIC CHARACTERISTICS

Common source; $T_{amb} = 25 \, ^{\circ}\text{C}$; unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
C _{is}	input capacitance	$V_{DS} = 20 \text{ V}; V_{GS} = -1 \text{ V}; f = 1 \text{ MHz}$	_	4	_	pF
C _{rs}	reverse transfer capacitance	$V_{DS} = 20 \text{ V}; V_{GS} = -1 \text{ V}; f = 1 \text{ MHz}$	_	1.1	_	pF
Cos	output capacitance	$V_{DS} = 20 \text{ V}; V_{GS} = -1 \text{ V}; f = 1 \text{ MHz}$	_	1.6	_	pF
9 _{is}	input conductance	$V_{DS} = 15 \text{ V}; V_{GS} = 0; f = 200 \text{ MHz}$	-	250	_	μS
gos	output conductance	$V_{DS} = 15 \text{ V}; V_{GS} = 0; f = 200 \text{ MHz}$	_	40	_	μS
y _{fs}	forward transfer admittance	$V_{DS} = 15 \text{ V}; V_{GS} = 0; f = 1 \text{ kHz}$	3	-	6.5	mS
		$V_{DS} = 15 \text{ V}; V_{GS} = 0; f = 200 \text{ MHz}$	_	6	_	mS
y _{rs}	reverse transfer admittance	$V_{DS} = 15 \text{ V}; V_{GS} = 0; f = 200 \text{ MHz}$	_	1.4	_	mS
y _{os}	output admittance	$V_{DS} = 15 \text{ V}; V_{GS} = 0; f = 1 \text{ kHz}$	_	25	_	μS
f _{gfs}	cut-off frequency	V_{DS} = 15 V; V_{GS} = 0; g_{fs} = 0.7 of its value at 1 kHz	_	700	_	MHz
F	noise figure	V_{DS} = 15 V; V_{GS} = 0; f = 100 MHz; R_G = 1 k Ω (common source); input tuned to minimum noise	-	1.5	_	dB

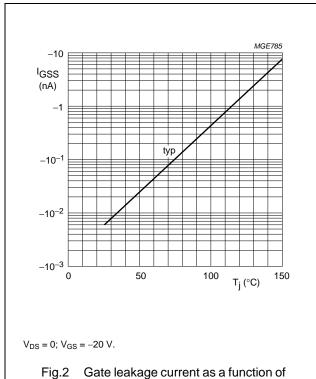
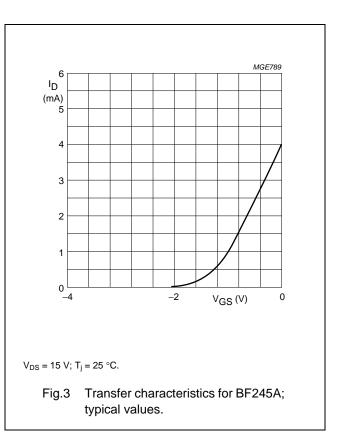
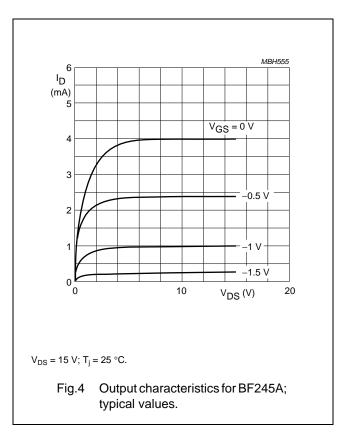


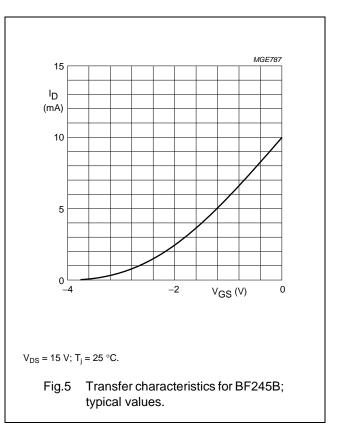
Fig.2 Gate leakage current as a function of junction temperature; typical values.

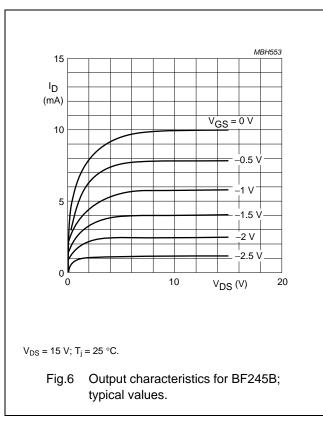


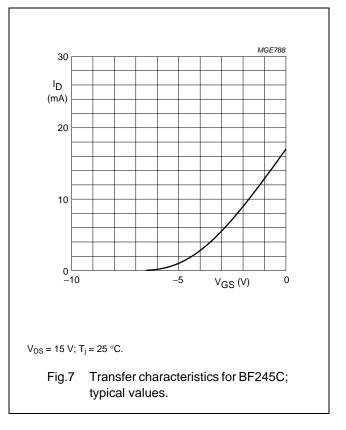
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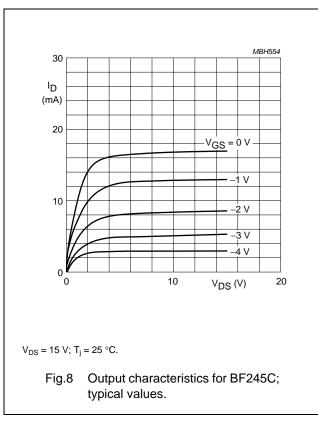


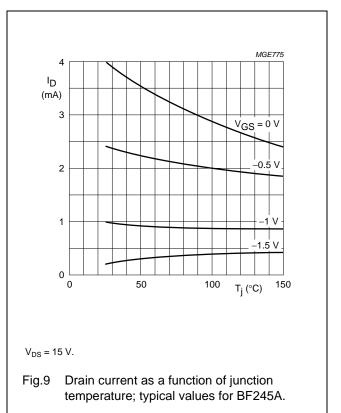


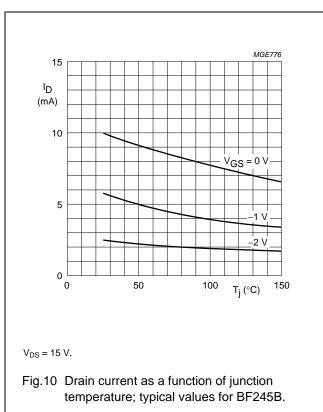


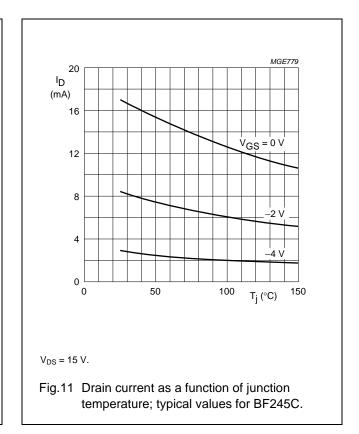
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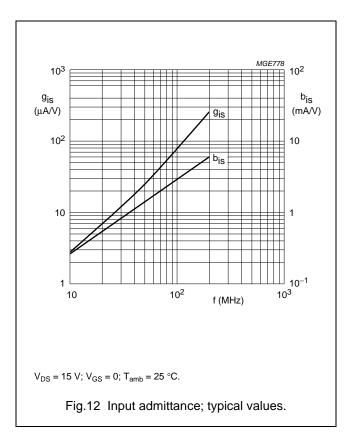






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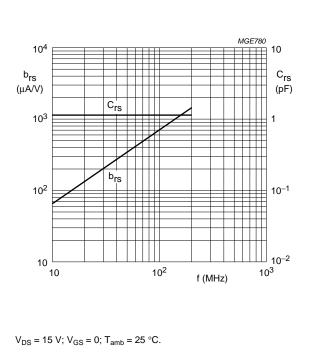
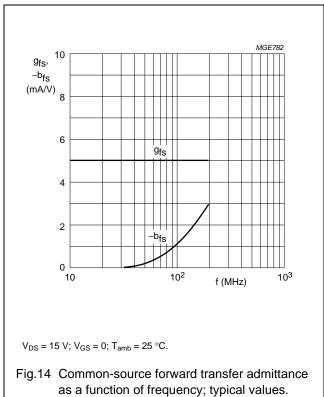
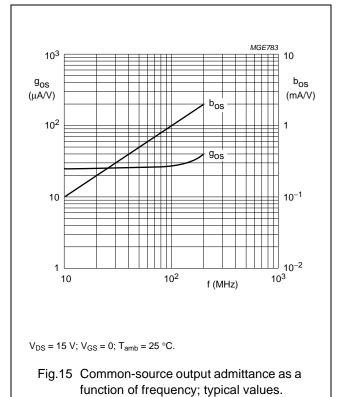


Fig.13 Common source reverse admittance as a function of frequency; typical values.





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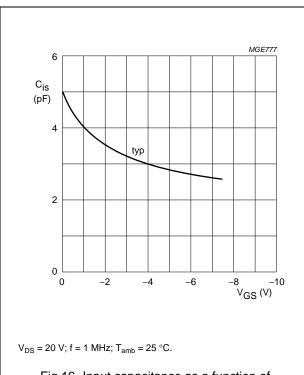


Fig.16 Input capacitance as a function of gate-source voltage; typical values.

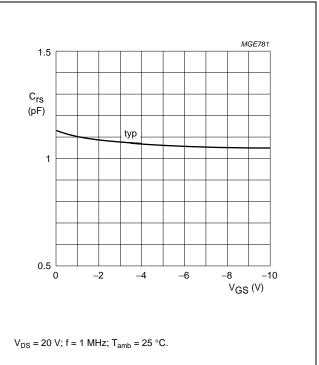
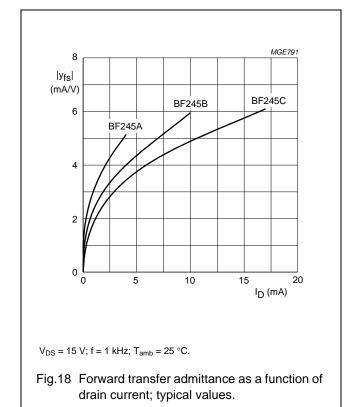
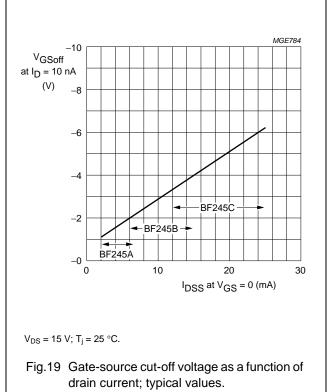


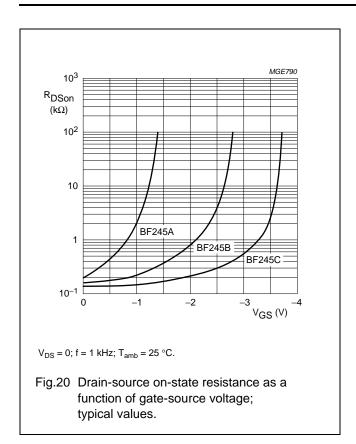
Fig.17 Reverse transfer capacitance as a function of gate-source voltage; typical values.

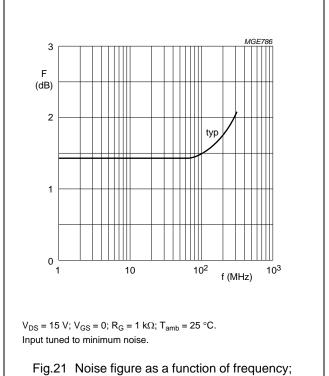




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typical values.

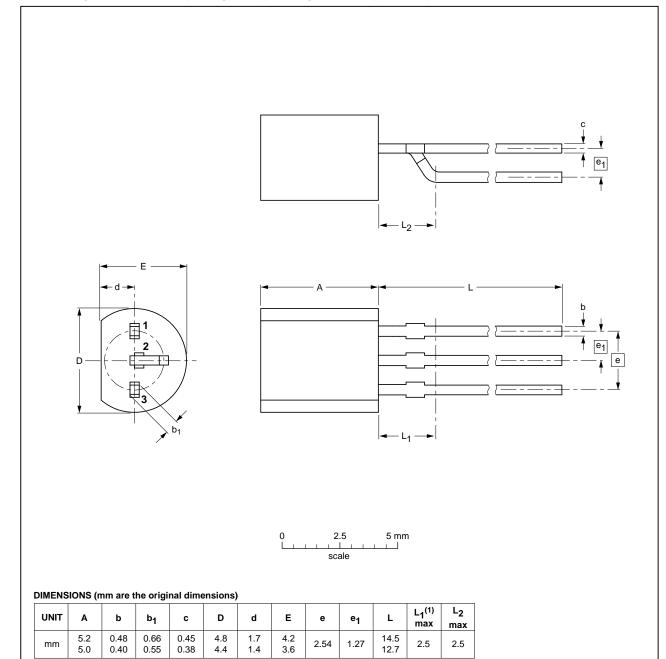
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PACKAGE OUTLINE

Plastic single-ended leaded (through hole) package; 3 leads (on-circle)

SOT54 variant



Note

1. Terminal dimensions within this zone are uncontrolled to allow for flow of plastic and terminal irregularities.

OUTLINE	REFERENCES			EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT54 variant						04-06-28 05-01-10

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DATA SHEET STATUS

DOCUMENT STATUS ⁽¹⁾	PRODUCT STATUS ⁽²⁾	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet	Production	This document contains the product specification.

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